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| Notice of References Cited | Application/Control No. 10/787,078 | Applicant(s)/Patent Under Reexamination HAYASHIBE ET AL. | |
| | Examiner Delma R. Flores Ruiz <i>DRF</i> | Art Unit 2828 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|------------------|----------------|
| * | A | US-2004/0161193 A1 | 08-2004 | Yee, Young-Joo | 385/031 |
| * | B | US-5,293,038 A | 03-1994 | Kadowaki et al. | 250/216 |
| * | C | US-2004/0190579 A1 | 09-2004 | Hayashibe et al. | 372/092 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
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